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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		MMBZ33VA-T						
		Part Description						
		Nexperia DHAM	Protection					
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
	PC	Bake Tamb = 125 °C	24 hours 168 hours					
# 11	Preconditioning	Soak Tamb = 85 °C, RH = 85% Reflow soldering	3 cycles	524	22040	0		
# A1	reconditioning	-	5 cycles	524	22940	0		
	HTRB	MIL-STD-750-1 M1038 Method A						
		$T_j = T_j max$, $Vr = 100\%$ of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	205	9400	0		
# DI			1000 110013	205	5400	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	156	7080	0		
	. , ,	2 ,	1000 0/000	100	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	0		
	UHAST	JESD22-A118						
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	0.5.1	156	7080	0		
		JESD22-A102	— 96 hours					
	AC	Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	Temperature Reverse Bias	rated reverse voltage ^[1]	1000 hours	156	7080	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta T j$ =						
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.		
	BOU	150000 4111						
"	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10	50	1700	•		
# C8		200 - C = 3 - C	10 s	56	1700	0		
# 610	SD Solderability	J-STD-002		50	1700	0		
# C10	Solderability	3-310-002		56	1700	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Protection	9400	0	0,45	2,21E+09

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